

MD12844: FASER and SND background mitigations

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Procedure

- Inject two indivs per beam, 1.4e11 ppb, both colliding in IP1
- Nominal ramp and squeeze to 60 cm
- Measure reference background 1h
- Change corrector magnets and measure background 1h
- Inverted V xing in IR1:
 - Move IR1 TCTPVs to parking
 - Invert xing angle sign
 - Realign TCTPV and put at nominal settings
 - Measure background 1h
- Horizontal xing in IR1:
 - Move TCTPH, TCTPV and TCL4 in IR1 to parking
 - Rotate to H xing
 - Realign TCTs / TCL4s and put at nominal settings
 - Measure background 1h
- n.b. abs xing angle will not exceed 160 µrad
- Total time: 6h





rMPP comments:

- Clarify masking and collimator thresholds:
 - Setup beam flag
 - "Standard" collimation masks (lossmaps, alignment...):
 - Maskable BLMs
 - Collimator positions, beta*, DOROS BPMs, and energy interlocks
 - IR1 TCTs and TCLs thresholds to parking
- Detail rotation of xing angle and tools
 - Standard OP tool written by Michi for adjusting xing knobs and update orbit feedback will be used
- Change of beam flags and interlocks should be YES





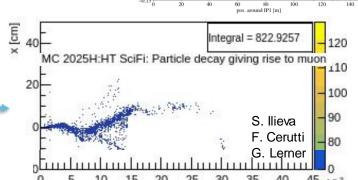
Introduction and Motivation

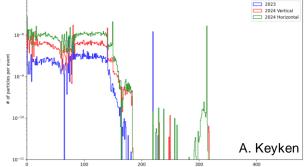
2024 configuration caused significant increase of muon background to FASER and SND

- Frequent change of emulsion plates
- Limited data taking
- Simulations (FLUKA / BDSIM) identified muon source between IP and TAN*:



- No mitigation method found at this moment
- Horizontal xing worsens the background:*
- Inverted sign of V xing?
- Corrector magnets upstream of TAN / DS?





- Measurements important to benchmark simulation with the second in future configurations)
 - MD goal: Measure background for different configurations
 - Main focus on configurations that reduce background, if found



